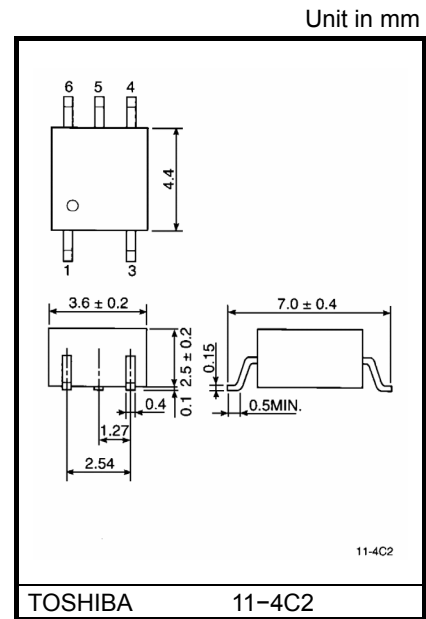


TLP112

- Digital Logic Isolation
- Line Receiver
- Switching Power Supply Feedback Control
- Transistor Inverter

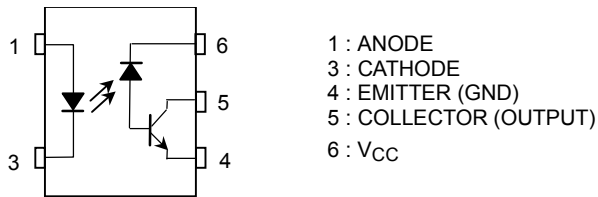
The TOSHIBA mini flat coupler TLP112 is a small outline coupler, suitable for surface mount assembly. TLP112 consists of a GaAlAs light emitting diode, optically coupled to a high speed detector of one chip photodiode-transistor.

- Isolation voltage: 2500 Vrms (min.)
- Switching speed: $t_{pHL} = 0.8\mu s$, $t_{pLH} = 2\mu s$ (max.)
($R_L = 4.1\text{ k}\Omega$)
- TTL compatible
- UL recognized: UL1577, file no. E67349

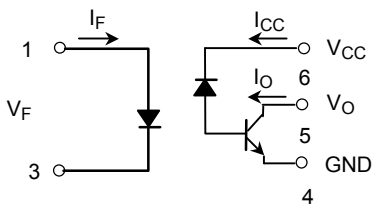


Weight: 0.09g

Pin Configuration (top view)



Schematic



Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit
LED	Forward current (Note 1)	I_F	25	mA
	Pulse forward current (Note 2)	I_{FP}	50	mA
	Peak transient forward current (Note 3)	I_{FPT}	1	A
	Reverse voltage	V_R	5	V
	Diode power dissipation (Note 4)	P_D	45	mW
Detector	Output current	I_O	8	mA
	Peak output current	I_{OP}	16	mA
	Supply voltage	V_{CC}	-0.5~15	V
	Output voltage	V_O	-0.5~15	V
	Output power dissipation (Note 5)	P_O	100	mW
Operating temperature range		T_{opr}	-55~100	°C
Storage temperature range		T_{stg}	-55~125	°C
Lead soldering temperature(10s)		T_{sol}	260	°C
Isolation voltage (AC, 1 min., R.H ≤ 60%, Note 6)		BVS	2500	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

(Note 1) Derate 0.8 mA / °C above 70°C.

(Note 2) 50% duty cycle, 1ms pulse width.

Derate 1.6mA / °C above 70°C.

(Note 3) Pulse width ≤ 1μs, 300pps.

(Note 4) Derate 0.9mW / °C above 70°C.

(Note 5) Derate 2mW / °C above 70°C.

Electrical Characteristics (Ta = 25°C)

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
LED	Forward voltage	V_F	$I_F = 16\text{mA}$	—	1.65	1.85	V
	Forward voltage temperature coefficient	$\Delta V_F / \Delta T_a$	$I_F = 16\text{mA}$	—	-2	—	mV / °C
	Reverse current	I_R	$V_R = 5\text{V}$	—	—	10	μA
	Capacitance between terminals	C_T	$V_F = 0, f = 1\text{MHz}$	—	45	—	pF
Detector	High level output current	$I_{OH(1)}$	$I_F = 0\text{mA}, V_{CC} = V_O = 5.5\text{V}$	—	3	500	nA
		$I_{OH(2)}$	$I_F = 0\text{mA}, V_{CC} = V_O = 15\text{V}$	—	—	5	μA
		I_{OH}	$I_F = 0\text{mA}, V_{CC} = V_O = 15\text{V}$ $T_a = 70^\circ\text{C}$	—	—	50	
	High level supply current	I_{CCH}	$I_F = 0\text{mA}, V_{CC} = 15\text{V}$	—	0.01	1	μA
Coupled	Current transfer ratio	I_O / I_F	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $V_O = 0.4\text{V}$	10	—	—	%
	Low level output voltage	V_{OL}	$I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$ $I_O = 1.1\text{mA}$	—	—	0.4	V
	Isolation resistance	R_S	R.H. $\leq 60\%$ $V_S = 500\text{V DC}$ (Note 6)	5×10^{10}	10^{14}	—	Ω
	Stray capacitance between input to output	C_S	$V_S = 0, f = 1\text{MHz}$ (Note 6)	—	0.8	—	pF

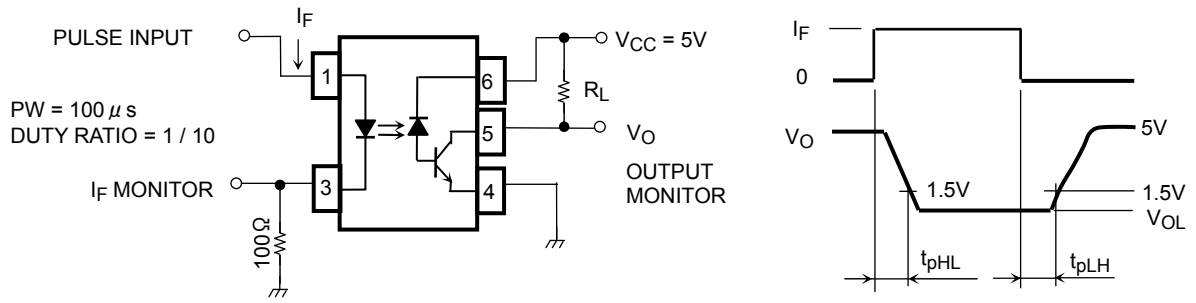
Switching Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min.	Typ.	Max.	Unit
Propagation delay time (H→L)	t_{pHL}	1	$I_F = 0 \rightarrow 16\text{mA}$ $V_{CC} = 5\text{V}, R_L = 4.1\text{k}\Omega$	—	—	0.8	μs
Propagation delay time (L→H)	t_{pLH}	1	$I_F = 16 \rightarrow 0\text{mA}$ $V_{CC} = 5\text{V}, R_L = 4.1\text{k}\Omega$	—	—	2.0	μs
Common mode transient immunity at high output level	CM_H	2	$I_F = 0\text{mA}, V_{CM} = 200\text{V}_{p-p}$ $R_L = 4.1\text{k}\Omega$	—	1500	—	V / μs
Common mode transient immunity at low output level	CM_L	2	$I_F = 16\text{mA}, V_{CM} = 200\text{V}_{p-p}$ $R_L = 4.1\text{k}\Omega$	—	-1500	—	V / μs

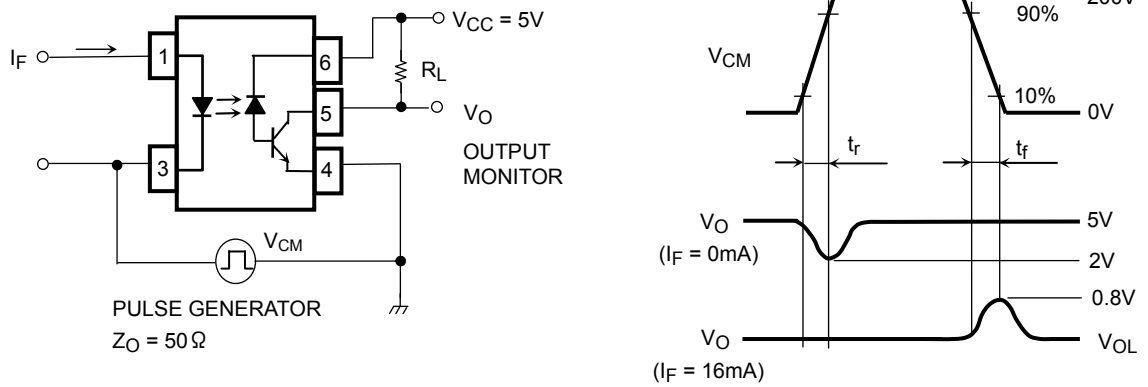
(Note 6) Device considered a two-terminal device: Pins 1 and 3 shorted together and Pin 4, 5 and 6 shorted together.

(Note 7) Maximum electrostatic discharge voltage for any pins: 100V (C=200pF, R=0)

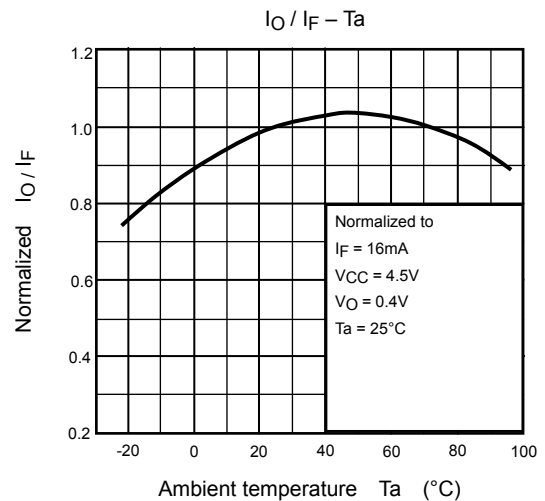
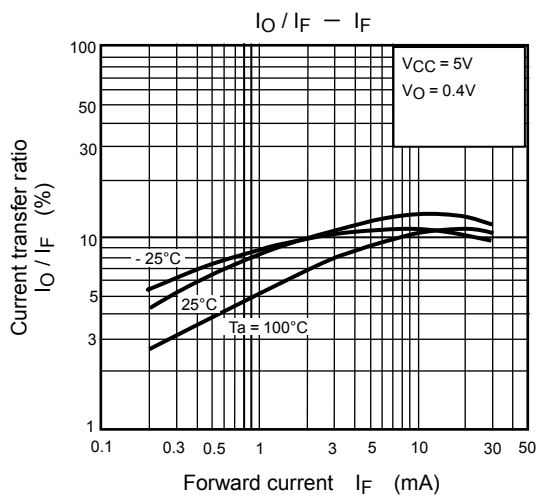
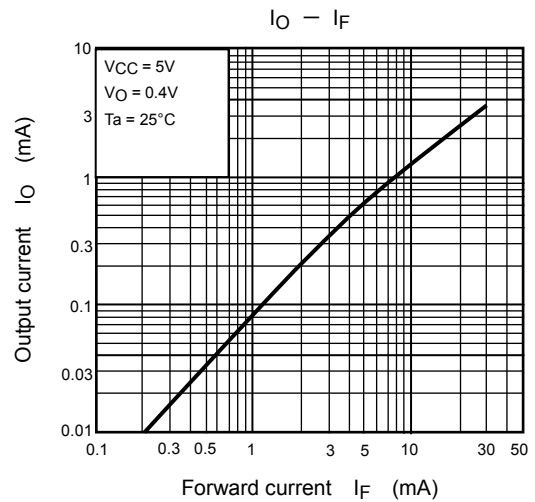
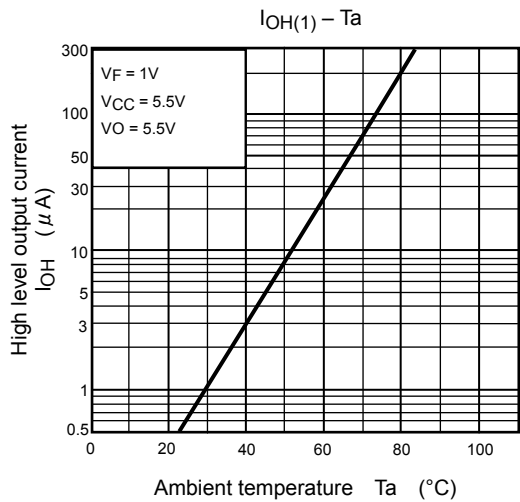
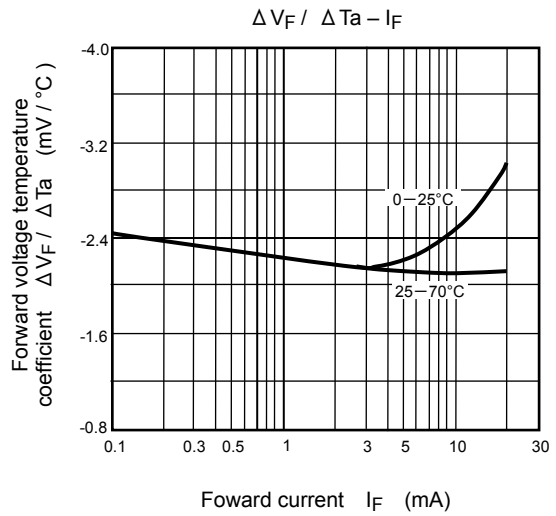
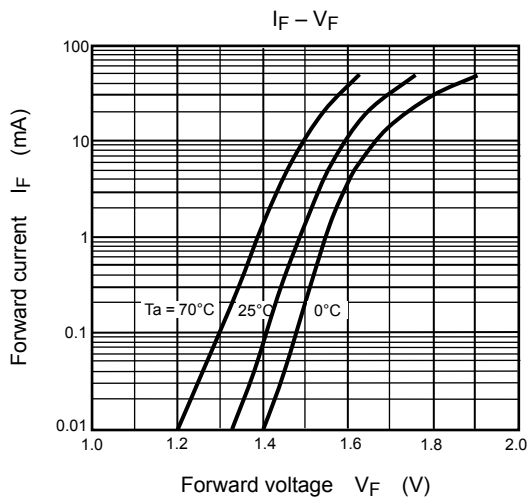
Test Circuit 1: Switching Time Test Circuit

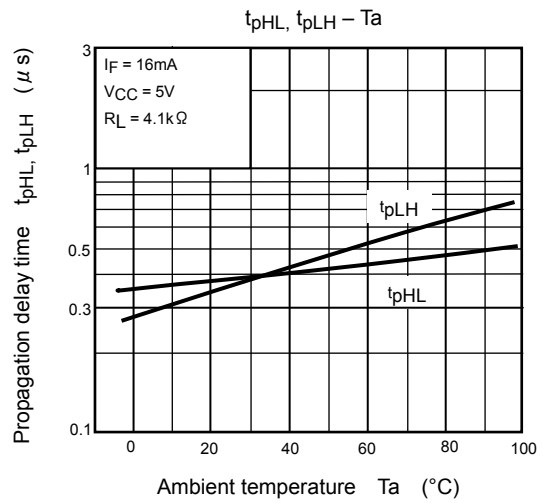
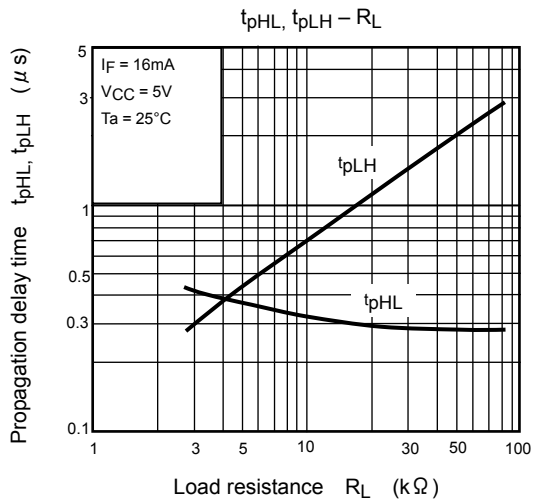
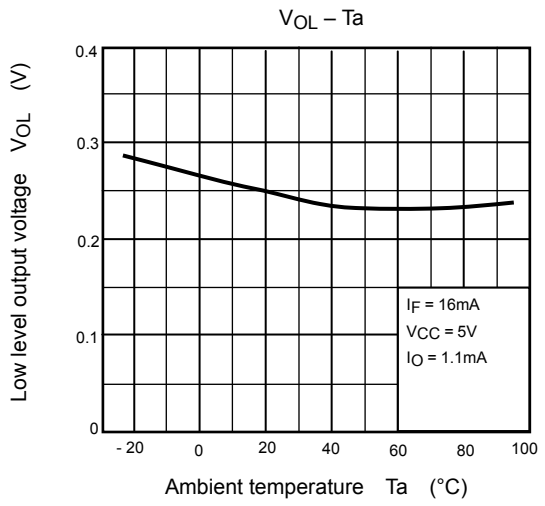
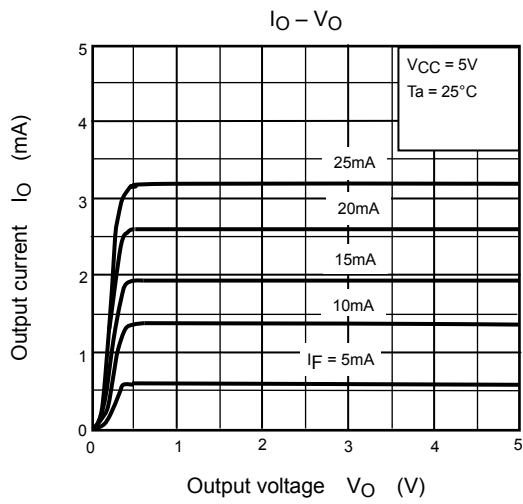


Test Circuit 2: Common Mode Transient Immunity Test Circuit



$$CM_H = \frac{160(V)}{t_r(\mu s)}, CM_L = \frac{160(V)}{t_f(\mu s)}$$





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20070701-EN

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